


<b>Search Notes</b> 	<b>Application/Control No.</b> 10781041	<b>Applicant(s)/Patent Under Reexamination</b> WANG ET AL.
	<b>Examiner</b> Betsy L. Deppe	<b>Art Unit</b> 2611

SEARCHED			
Class	Subclass	Date	Examiner
375	260	7/3/08	B. Deppe
370	208, 210, 343, 344, 480	7/3/08	B. Deppe

SEARCH NOTES		
Search Notes	Date	Examiner
Text search (USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM-TDB)	7/3/08	B. Deppe

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner